Prober Sunlab sheet resistance scanner

Short description: Sunlab Sherescan High resolution (selective) emitter sheet resistance mapping.

Features:

Measurement range: 10-200 Ohms/sq
Wafer dimensions & shapes: max 210mm, thickness 100-1000 µm, square, semi square, round
Four point probe: Jandel cylindrical probe head, pin spacing 0.635 mm, load (per needle) 100g, needle radius 100µm
Wafer fixation: vacuum

Localisation: ESD BENCH 9

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